

<b>Notice of References Cited</b>	Application/Control No. 10/724,641	Applicant(s)/Patent Under Reexamination PIERRE DIERICKX ET AL	
	Examiner Deborah Yee	Art Unit 1742	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,558,483	05-2003	Nakamura et al.	148/332
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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